

# N-channel silicon junction FETs

J108; J109; J110

## FEATURES

- High speed switching
- Interchangeability of drain and source connections
- Low  $R_{DSon}$  at zero gate voltage ( $<8 \Omega$  for J108).

## APPLICATIONS

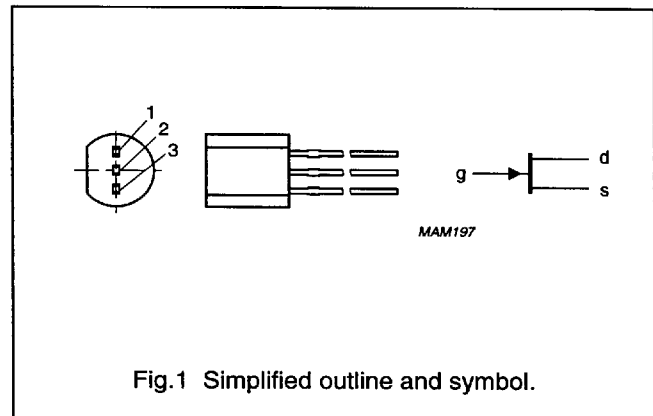
- Analog switches
- Choppers and commutators.

## DESCRIPTION

N-channel symmetrical silicon junction field-effect transistors in a TO-92 package.

## PINNING - TO-92

PIN	SYMBOL	DESCRIPTION
1	g	gate
2	s	source
3	d	drain



### CAUTION

The device is supplied in an antistatic package. The gate-source input must be protected against static discharge during transport or handling.

## QUICK REFERENCE DATA

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
$V_{DS}$	drain-source voltage		–	$\pm 25$	V
$V_{GSoff}$	gate-source cut-off voltage	$I_D = 1 \mu A; V_{DS} = 5 V$			
	J108		–3	–10	V
	J109		–2	–6	V
	J110		–0.5	–4	V
$I_{DSS}$	drain current	$V_{GS} = 0; V_{DS} = 5 V$			
	J108		80	–	mA
	J109		40	–	mA
	J110		10	–	mA
$P_{tot}$	total power dissipation	up to $T_{amb} = 50 \text{ }^\circ\text{C}$	–	400	mW

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**LIMITING VALUES**

In accordance with the Absolute Maximum Rating System (IEC 134).

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
$V_{DS}$	drain-source voltage		–	±25	V
$V_{GSO}$	gate-source voltage	open drain	–	–25	V
$V_{GDO}$	gate-drain voltage	open source	–	–25	V
$I_G$	forward gate current (DC)		–	50	mA
$P_{tot}$	total power dissipation	up to $T_{amb} = 50\text{ °C}$	–	400	mW
$T_{stg}$	storage temperature		–65	150	°C
$T_j$	operating junction temperature		–	150	°C

**THERMAL CHARACTERISTICS**

SYMBOL	PARAMETER	VALUE	UNIT
$R_{th\ j-a}$	thermal resistance from junction to ambient	250	K/W

**STATIC CHARACTERISTICS** $T_j = 25\text{ °C}$ ; unless otherwise specified.

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
$V_{(BR)GSS}$	gate-source breakdown voltage	$I_G = -1\ \mu\text{A}$ ; $V_{DS} = 0$	–	–	–25	V
$V_{GSoff}$	gate-source cut-off voltage	$I_D = 1\ \mu\text{A}$ ; $V_{DS} = 5\text{ V}$				V
	J108		–3	–	–10	V
	J109		–2	–	–6	V
	J110		–0.5	–	–4	V
$I_{DSS}$	drain current	$V_{GS} = 0$ ; $V_{DS} = 15\text{ V}$				mA
	J108		80	–	–	mA
	J109		40	–	–	mA
	J110		10	–	–	mA
$I_{GSS}$	gate leakage current	$V_{GS} = -15\text{ V}$ ; $V_{DS} = 0$	–	–	–3	nA
$I_{DSX}$	drain-source cut-off current	$V_{GS} = -10\text{ V}$ ; $V_{DS} = 5\text{ V}$	–	–	3	nA
$R_{DSon}$	drain-source on-state resistance	$V_{GS} = 0$ ; $V_{DS} = 100\text{ mV}$				Ω
	J108		–	–	8	Ω
	J109		–	–	12	Ω
	J110		–	–	18	Ω

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**DYNAMIC CHARACTERISTICS**

$T_j = 25\text{ }^\circ\text{C}$ ; unless otherwise specified.

SYMBOL	PARAMETER	CONDITIONS	TYP.	MAX.	UNIT
$C_{is}$	input capacitance	$V_{DS} = 0; V_{GS} = -10\text{ V}; f = 1\text{ MHz}$	15	30	pF
		$V_{DS} = 0; V_{GS} = 0; f = 1\text{ MHz}; T_{amb} = 25\text{ }^\circ\text{C}$	50	85	pF
$C_{rs}$	reverse transfer capacitance	$V_{DS} = 0; V_{GS} = -10\text{ V}; f = 1\text{ MHz}$	8	15	pF
<b>Switching times; see Fig.2</b>					
$t_d$	delay time	note 1	2	–	ns
$t_{on}$	turn-on time		4	–	ns
$t_s$	storage time		4	–	ns
$t_{off}$	turn-off time		6	–	ns

**Note**

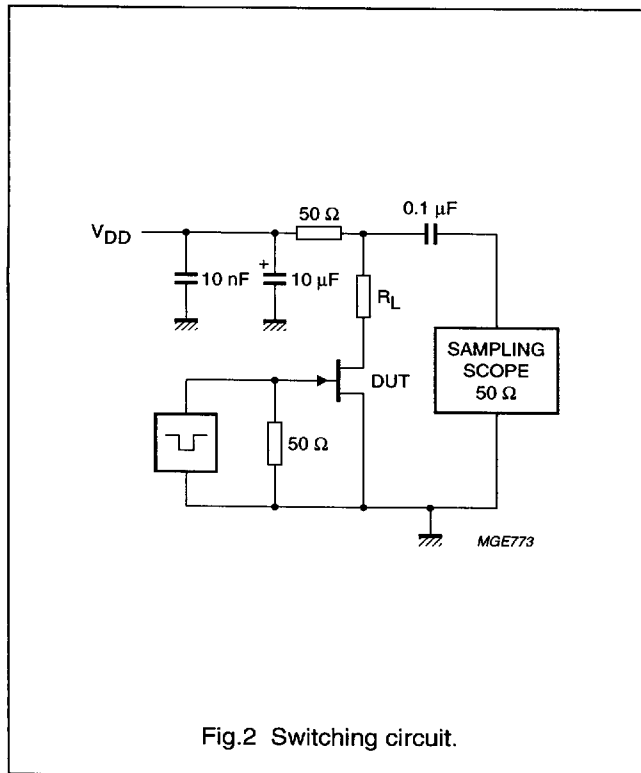
1. Test conditions for switching times are as follows:

$V_{DD} = 1.5\text{ V}; V_{GS} = 0\text{ to }V_{GSoff}$  (all types)

$V_{GSoff} = -12\text{ V}; R_L = 100\text{ }\Omega$  (J108)

$V_{GSoff} = -7\text{ V}; R_L = 100\text{ }\Omega$  (J109)

$V_{GSoff} = -5\text{ V}; R_L = 100\text{ }\Omega$  (J110).



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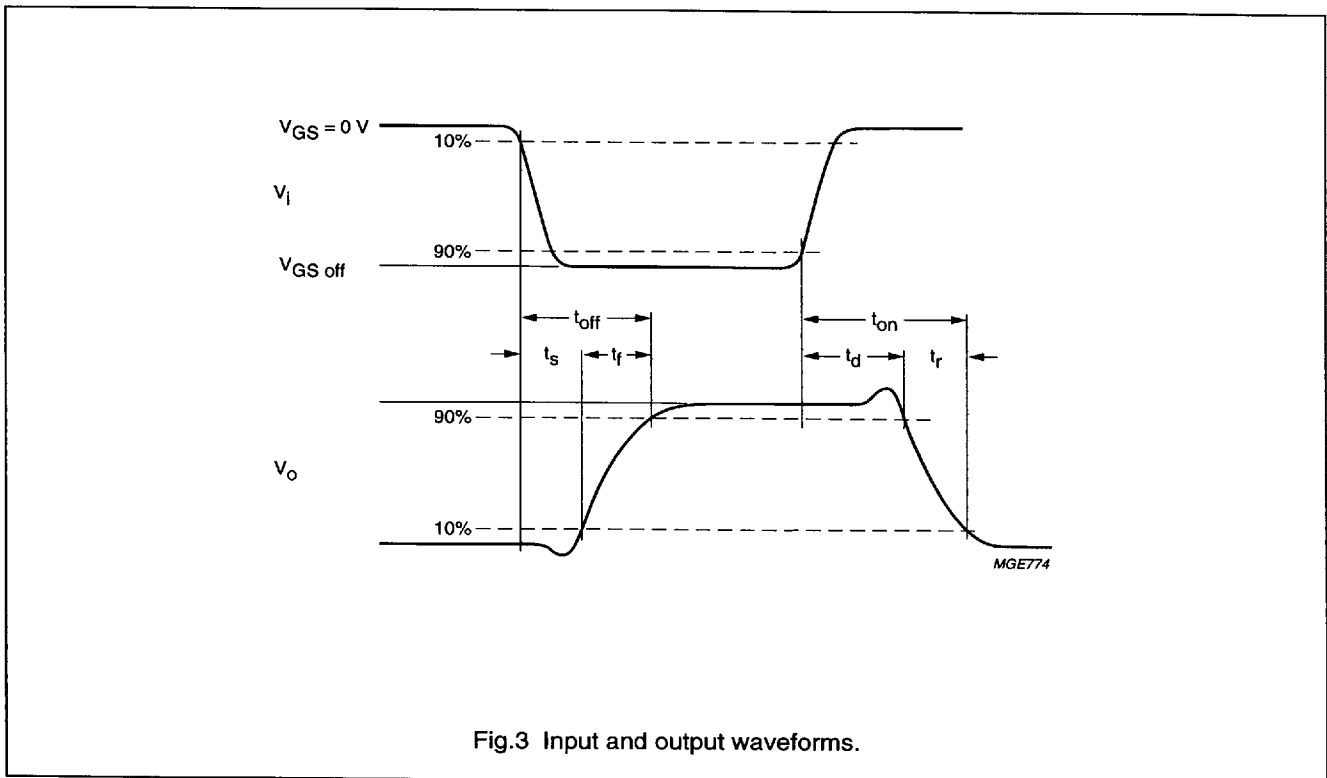


Fig.3 Input and output waveforms.

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PACKAGE OUTLINE

